
Merjenje upornosti v normalnem stanju in merjenje kritičnega toka - Spoj "High-Tc Josephson" (IEC 61788-22-2:2021)

Normal state resistance and critical current measurement - High-Tc Josephson junction (IEC 61788-22-2:2021)

Supraleitfähigkeit - Teil 22-2: Messung des Normalleitungswiderstands und des kritischen Stroms - HTS Josephson Kontakt (IEC 61788-22-2:2021)

Mesure de la résistance à l'état normal et du courant critique - Jonction Josephson à Tc élevée (IEC 61788-22-2:2021)

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NORME EUROPÉENNE
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Superconductivity - Part 22-2: Normal state resistance and
critical current measurement - High- T_C Josephson junction
(IEC 61788-22-2:2021)

Supraconductivité - Partie 22-2: Mesure de la résistance à
l'état normal et du courant critique - Jonction Josephson à
 T_C élevée
(IEC 61788-22-2:2021)

Supraleitfähigkeit - Teil 22-2: Messung des
Normalleitungswiderstands und des kritischen Stroms -
HTS Josephson Kontakt
(IEC 61788-22-2:2021)

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EN IEC 61788-22-2:2021 (E)**European foreword**

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Annex ZA (normative)

Normative references to international publications with their corresponding European publications

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NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 61788-22-1	-	Superconductivity - Part 22-1: Superconducting electronic devices - Generic specification for sensors and detectors	EN 61788-22-1	-
IEC 60050-815	2015	International Electrotechnical Vocabulary - - Part 815: Superconductivity	-	-
IEC 60617	-	Graphical symbols for diagrams	-	-

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NORME INTERNATIONALE



iTeh STANDARD

Superconductivity –

Part 22-2: Normal state resistance and critical current measurement –

High- T_c Josephson junctions

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Supraconductivité –

Partie 22-2: Mesurage de la résistance à l'état normal et du courant critique –

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CONTENTS

FOREWORD.....	4
INTRODUCTION.....	6
1 Scope.....	7
2 Normative references	7
3 Terms and definitions	7
4 Symbols	8
5 Principle of measurement method.....	9
6 Apparatus.....	9
6.1 General.....	9
6.2 Cryogenic system	9
6.3 Electrical measurement system.....	10
6.4 Circuitry	10
7 Estimation of normal state resistance (R_n) and intrinsic critical current (I_{ci}).....	11
7.1 Calculation method	11
7.2 Geometric mean criterion for hyperbolic function fitting	12
8 Standard uncertainty	12
8.1 General.....	12
8.2 Type A uncertainty.....	12
8.3 Type B uncertainty.....	14
8.3.1 General	14
8.3.2 Temperature.....	14
8.3.3 Voltage measurement.....	16
8.3.4 Current measurement.....	16
8.4 Budget table.....	17
8.5 Uncertainty requirement.....	18
9 Test report.....	18
9.1 Identification of test device	18
9.2 R_n value.....	18
9.3 I_{ci} value.....	18
9.4 Standard uncertainty.....	18
9.5 Atmospheric pressure	18
9.6 Miscellaneous optional report	18
Annex A (informative) Calculation technique and practical application to high- T_c Josephson junctions	20
A.1 General.....	20
A.2 Hyperbolic function fitting method	20
A.3 Geometric mean method	21
A.4 Combined method.....	22
A.5 Estimation of R_n , I_{ci} , $u_{A,R}$ and $u_{A,I}$	23
A.5.1 General	23
A.5.2 High- T_c Josephson junction (JL350)	23
A.5.3 High- T_c Josephson junction (JL351)	25
A.5.4 High- T_c Josephson junction (TUT).....	27
Annex B (informative) Practical application to low- T_c Josephson junctions.....	30

B.1	General.....	30
B.2	Estimation of R_n , I_{ci} , $u_{A,R}$ and $u_{A,I}$	30
B.2.1	General	30
B.2.2	Low- T_C Josephson junction (IU1)	30
B.2.3	Low- T_C Josephson junction (IU2)	31
B.2.4	Low- T_C Josephson junction (IU3)	32
B.2.5	Low- T_C Josephson junction (IU4)	34
	Bibliography.....	35
	Figure 1 – Typical circuitry for voltage-current ($U-I$) characteristic curve measurement	10
	Figure 2 – Ideal $U-I$ characteristic curve (red line) and hyperbolic function (RSJ) model curve (dotted line).....	11
	Figure 3 – Geometric mean criterion and RSJ model fitting for TUT-JJ05 at 75,8 K.....	15
	Figure 4 – Geometric mean criterion and RSJ model fitting for TUT-JJ05 at 76,3 K.....	16
	Figure A.1 – $U-I$ curve based on resistively shunted junction (RSJ) model	21
	Figure A.2 – $U-I$ curve affected by noise-rounding and self-heating	21
	Figure A.3 – Application of geometric mean method to ideal $U-I$ in Figure A.1	22
	Figure A.4 – Application of geometric mean method to $U-I$ with noise-rounding and self-heating effects in Figure A.2.....	23
	Figure A.5 – $U-I$ curve of JL350	24
	Figure A.6 – Application of geometric mean method to Figure A.5	24
	Figure A.7 – Result of RSJ model fitting for JL350	25
	Figure A.8 – $U-I$ curve of JL351	26
	Figure A.9 – Application of geometric mean method to Figure A.8	26
	Figure A.10 – Result of RSJ model fitting for JL351	27
	Figure A.11 – $U-I$ curve of TUT with a small I_m	28
	Figure A.12 – Application of geometric mean method to TUT	28
	Figure A.13 – Application of adjusted geometrical mean method to TUT	29
	Figure A.14 – Result of RSJ model fitting for TUT	29
	Figure B.1 – Application of geometric mean method to IU1	31
	Figure B.2 – Result of RSJ model fitting for IU1	31
	Figure B.3 – Application of geometric mean method to IU2	32
	Figure B.4 – Result of RSJ model fitting for IU2	32
	Figure B.5 – Application of geometric mean method to IU3	33
	Figure B.6 – Result of RSJ model fitting for IU3	33
	Figure B.7 – Application of geometric mean method to IU4	34
	Figure B.8 – Result of RSJ model fitting for IU4	34
	Table 1 – Typical relative standard Type A uncertainty for high- T_C Josephson junctions	14
	Table 2 – Budget table for R_n	17
	Table 3 – Budget table for I_{ci}	17
	Table A.1 – R_n , I_{ci} , $u_{A,R}$ and $u_{A,I}$ values of high- T_C Josephson junctions	23
	Table B.1 – R_n , I_{ci} , $u_{A,R}$ and $u_{A,I}$ values of low- T_C Josephson junctions.....	30

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SUPERCONDUCTIVITY –

Part 22-2: Normal state resistance and critical current measurement – High- T_c Josephson junction

FOREWORD

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The text of this International Standard is based on the following documents:

FDIS	Report on voting
90/484/FDIS	90/486/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/standardsdev/publications.

A list of all parts in the IEC 61788 series, published under the general title *Superconductivity*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under webstore.iec.ch in the data related to the specific document. At this date, the document will be

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INTRODUCTION

IEC 61788-22 (all parts) is a series of International Standards on superconductor electronic devices. Superconductivity offers various possibilities of realizing sensors and detectors for a variety of measurands. Several types of superconductor sensors and detectors have been developed, using such features as superconducting energy gaps, sharp normal-superconducting transition, nonlinear current-voltage characteristics, superconducting coherent states and quantization of magnetic flux. Superconductors are influenced by interaction with electromagnetic fields, photons, ions, etc. The superconductor sensors and detectors have extremely high performance in resolution, time response and sensitivity, which cannot be realized by any other sensors and detectors.

IEC 61788-22-1 lists various types of superconductor sensors and detectors. A key element of some sensors and detectors is Josephson junction. The superconductor material types used for Josephson junctions are divided into two categories: low- T_c superconductor (LTS) and high- T_c superconductor (HTS). This document (IEC 61788-22-2) defines a measurement method of normal state resistance (R_n) and intrinsic critical current (I_{ci}) of HTS Josephson junctions, which are used for magnetic measurement with superconductor quantum interference device (SQUID), detection of millimetre to terahertz band radiation and other applications.

The measurement method covered in this document is intended to give an appropriate and agreeable technical base for those engineers working in the field of superconductor technology. Although the mechanism of high- T_c superconductivity is under investigation, the occurrence of the Josephson effect in such weak link structures as bicrystal, step-edge and ramp edge is reliable, and characteristic parameters for conventional LTS Josephson junctions are valid also for HTS Josephson junctions. The important parameters of HTS Josephson junctions for designing superconductor devices are normal state resistance (R_n) and critical current (I_c), which are combined as $I_c R_n$ product that is obtained experimentally. At this moment, most HTS Josephson junctions exhibit a non-hysteretic characteristic voltage-current ($U-I$) curve, which is typical for superconductor/normal-conductor/superconductor (SNS) junctions. On $U-I$ curves, two types of distortions are often observed: noise-rounding and self-heating effects. Especially, maximum current values without voltage drop on the $U-I$ curves are often considerably reduced because of the noise-rounding effect, and therefore it is difficult to estimate an intrinsic critical current value. This document provides a method to obtain intrinsic values by selecting a data set range to eliminate the distortions and by fitting a model function even when two effects are present.

The critical current obtained by this standard method is therefore called intrinsic critical current with the variable symbol of I_{ci} , eliminating the noise-rounding effect on $U-I$ curves. On the other hand, the normal state resistance is insensitive to the noise rounding and it is possible to avoid the self-heating effect, so that the variable symbol R_n is used. The $I_{ci} R_n$ product is more essential for designing superconductor devices than the $I_c R_n$ product. I_{ci} values estimated by this document are usually higher than experimental I_c values.

Practical application of this document to HTS Josephson junctions is shown in Annex A. The estimation method in this document is applied to SNS-type LTS Josephson junctions to check universality in Annex B.

SUPERCONDUCTIVITY –

Part 22-2: Normal state resistance and critical current measurement – High- T_c Josephson junction

1 Scope

This part of IEC 61788 is applicable to high- T_c Josephson junctions. It specifies terms, definitions, symbols and the measurement and estimation method for normal state resistance (R_n) and intrinsic critical current (I_{ci}), based on a combination of selecting a data set from measured U – I curves with a geometric mean criterion and fitting a hyperbolic function to that data set.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 61788-22-1, *Superconductivity – Part 22-1: Superconducting electronic devices – Generic specification for sensors and detectors*

IEC 60617, *Graphical symbols for diagrams*: available at <http://std.iec.ch/iec60617>

IEC 60050-815:2015, *International Electrotechnical Vocabulary – Part 815: Superconductivity*: (available at <http://www.electropedia.org/>)

3 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>

3.1

U – I characteristic curve

V – I characteristic curve

I – V characteristic curve

data set of voltage drop between two superconductors of a Josephson junction and current applied to the junction